

IDS_ 11/25/03

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) POU920030178US1		Application Number NYA		
				Applicant(s) Motika, et al.				
				Filing Date NYA		Group Art Unit NYA		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
PC	1	3,761,695	09-25-1973	Eichelberger	235	153	08-16-1972	
PC	2	4,503,537	03-05-1985	McAnney	371	25	11-08-1982	
PC	3	4,513,418	04-23-1985	Bardell et al.	371	25	11-08-1982	
PC	4	4,598,401	07-01-1986	Whelan	371	25	06-25-1984	
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PC	7	5,528,602	06-18-1996	West et al.	371	22.4	03-09-1995	
PC	8	5,983,380	11-09-1999	Motika et al.	714	733	09-16-1997	
PC	9	6,311,311B1	10-30-2001	Swaney et al.	716	4	08-19-1999	
PC	10	6,401,226B1	06-04-2002	Maeno	714	728	07-08-1999	
PC	11	6,442,723B1	08-27-2002	Koprowski et al.	714	732	05-12-1999	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
PC	12	JP8005711A	1996-01-12	Japan	G01R31	28		✓
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
PC		W.H. Mcanney and J. Savir, "Built-In Checking of the Correct Self-Test Signature", September 1988, IEEE Transactions on Computers, Vol. 37, No. 9, pp. 1142-1145						
PC		J. Savir and William H. McAnney, "A Multiple Seed Linear Feedback Shift Register", February 1992, IEEE Transactions on Computers, Vol. 41, No. 2, pp. 250-252						
EXAMINER /Phung Chung/				DATE CONSIDERED 12/06/2006				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

